

<b>Notice of References Cited</b>		Application/Control No. 10/708,949	Applicant(s)/Patent Under Reexamination FAN ET AL.	
		Examiner David Garcia Cervetti	Art Unit 2136	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0021418 A1	01-2003	Arakawa et al.	380/277
*	C	US-7,392,385 B2	06-2008	Yoshimura et al.	713/168
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	K	US-			
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**NON-PATENT DOCUMENTS**

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